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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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of 2 Sheet

Complete If Known				
Application Number	10/809,317			
Filing Date	03/24/2004			
First Named Inventor	G. Ramanath			
Group Art Unit	2813			
Examiner Name	-Kielen, Erikt Colleen Rode			
Attorney Docket Number	5002.02-1			

U.S. PATENT DOCUMENTS					
Examiner Cite No.'	Cir-	Document Number Number - Kind Code ² (if known)	Publication Date/ Issue Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	No.				
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(2)	AC	US - 5,077,085	12-1991	Schnur et al.	
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Examinar	Cite	Foreign Patent Document		Name of Patentee or	Pages, Columns, Lines, Where Relevant	
	No.1	Country Code ³ - Number ⁴ - Kind Code ⁵ (# known)	Publication Date MM-DD-YYYY	Applicant of Cited Document	Passages or Relevant Figures Appear	T ⁰

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS				
Examiner Initials *	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²	
Œ	AL	Ahrens, C. et al., "Electrical characterization of conductive and non-conductive barrier layers for Cu-metallization," Applied Surface Science, 1995, pp. 285-290, Vol. 91.		
(De)	АМ	Ding, P.J. et al., "Effects of the addition of small amounts of AI to copper: Corrosion, resistivity, adhesion, morphology, and diffusion," J. Appl. Phys., April 1994, pp. 3627-3631, Vol. 75(7).		
æ	AN	Ding, P.J. et al., "Oxidation resistant high conductivity copper films," Appl. Phys. Lett. May 1994, pp. 2897-2899, Vol. 64(21).		
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Examiner Signature	College Qof	Date Considered	12/1/05

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Sheet

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Examiner Name	Kielen, Erikt Colleen Da			
Altomay Docket Number	5002.02-1			

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